

<b>Notice of References Cited</b>	Application/Control No. 10/811,007		Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner JONATHAN G. STERRETT		Art Unit 3623	Page 1 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,151,582	11-2000	Huang et al.	705/8
*	B	US-5,970,465	10-1999	Dietrich et al.	705/7
*	C	US-4,744,028	05-1988	Karmarkar, Narendra K.	705/8
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Brown, et al; "A Centralized Approach to Factory Simulation", 1997, Future Fab International, pp.1-9
	V	Jain, et al; "Criticality of Detailed Modelling in Semiconductor Supply Chain Simulation", Proceedings of the 1999 Winter Simulation Conference, pp.1-9.
	W	Rasmussen; "Integration simulation with activity-based management to evaluate manufacturing cell part sequencing", 1999, Computers & Industrial Engineering 37, pp.757-768.
	X	Spedding, T.A.; Sun, G.Q.; "Application of discrete event simulation to the activity based costing of manufacturing systems", 1999, International Journal of Production Economics, 58, pp.289-301.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/811,007		Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner JONATHAN G. STERRETT		Art Unit 3623	Page 2 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Takakuwa, Soemon; "The use of Simulation in Activity-based costing for flexible manufacturing systems", 1997, Proceedings of the 1997 Winter Simulation Conference, pp. 793-800.
	V	Miller, David J; "Simulation of a semiconductor manufacturing line", October 1990, Proceedings of the ACM, Vol. 33, No. 10, pp.99-108.
	W	Hood, Sarah J; Welch, Peter D; "Response Surface Methodology and Its Application in Simulation", Proceedings of the 1993 Winter Simulation Conference, pp.115-122.
	X	Czarnecki, Hank; Schroer, Bernard J; Rahman, M. Mizzanur; "Using Simulation to Schedule Manufacturing Resources", 1997, Proceedings of the 1997 Winter Simulation Conference, pp. 750-757.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/811,007		Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner JONATHAN G. STERRETT		Art Unit 3623	Page 3 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Whitman, Larry; Huff, Brian; Palaniswamy, Senthil; "Commercial Simulation over the Web", 1998, Proceedings of the 1998 Winter Simulation Conference, pp. 335-339
	V	Nembhard, Harriet Black; Kao, Ming-Shu; Lim, Gino; "Integrating Discrete-Event Simulation with Statistical Process Control Charts for Transitions in a Manufacturing Environment", 1999, Proceedings of the 1999 Winter Simulation Software, pp. 701-708.
	W	Potoradi, et al; "Determining Optimal Lot size for a Semiconductor back-end Factory", 1999, Proceedings of the 1999 Winter Simulation Conference, pp. 720-726.
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.